



JAB



Testing Laboratory
**Accreditation
Certificate**

Accreditation No. RTL02730

**Panasonic Corporation
Analysis Center EMC Test Laboratory**

1048, Kadoma, Kadoma-shi, Osaka, 571-8686 Japan

meets the following criteria. On the basis of this, Japan Accreditation Board (JAB) grants accreditation to the said testing laboratory.

Applicable accreditation criteria	: JIS Q 17025:2005 (ISO/IEC 17025:2005)
Scope of accreditation	: Electrical testing (As described in the appendix)
Premises covered by accreditation	: As described in the appendix.
Expiry date of accreditation	: September 30, 2016

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system.

The management system requirements in ISO/IEC 17025:2005 meet the principles of ISO 9001:2008 and are aligned with its pertinent requirements.

Renewed (3)

July 15, 2014

Initial accreditation

September 22, 2008

T. Oda, Chairman
Laboratory Accreditation Committee

H. Kume, President
Japan Accreditation Board

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Type of Laboratory	Testing Laboratory
Name of Laboratory	Panasonic Corporation Analysis Center EMC Test Laboratory
Address	1048, Kadoma, Kadoma-shi, Osaka, 571-8686 Japan

1) Premises on which testing activities are performed

Name of Premise	Panasonic Corporation Analysis Center EMC Test Laboratory Kadoma EMC Site	
Address of Premise	Zip	571-8686
	Address	1048, Kadoma, Kadoma - shi, Osaka, Japan
Testing service at permanent facilities or on site testing service	<input checked="" type="checkbox"/> Testing service at permanent facilities <input type="checkbox"/> On site testing service	

Scope of Accreditation

CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.1 Continuous disturbance tests	ANSI C63.4 with FCC method 47 CFR Part 15 subpart B CISPR 11 (except 10, 12) EN 55011 (except 10, 12) AS/NZS CISPR 11 (except 10, 12) CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) CISPR 15 (except 10) EN 55015 (except 10) AS/NZS CISPR 15 (except 10) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR22 (except 7) CISPR 32(only Table A.8,A.9) EN 55032(only Table A.8,A.9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61326-1, EN 61326-1



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Name of Laboratory	Panasonic Corporation Analysis Center EMC Test Laboratory
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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	VCCI Technical requirements IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.3 Discontinuous disturbance tests	CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11)
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.4 Conducted emission tests at telecommunication ports	CISPR 15 (except 10) EN 55015 (except 10) AS/NZS CISPR 15 (except 10) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR 22 (except 7) CISPR 32(only Table A.10,A.11) EN 55032(only Table A.10,A.11) IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) VCCI Technical requirements IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.5 Magnetic field test (Less than 30 MHz)	CISPR 11 (except 10, 12) EN 55011 (except 10, 12) AS/NZS CISPR 11 (except 10, 12) CISPR 15 (except 10) EN 55015 (except 10) AS/NZS CISPR 15 (except 10)

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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	IEC 60669-2-1 26 EN 60669-2-1 26
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.6 Electric field test (30 MHz to 1 GHz)	ANSI C63.4 with FCC method 47 CFR Part 15 subpart B CISPR 11 (except 10, 12) EN 55011 (except 10, 12) AS/NZS CISPR 11 (except 10, 12) CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) CISPR 15 (30 MHz to 300 MHz) EN 55015 (30 MHz to 300 MHz) AS/NZS CISPR 15 (30 MHz to 300 MHz) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR 22 (except 7) CISPR 32(only Table A.2,A.4) EN 55032(only Table A.2,A.4) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61326-1 EN 61326-1 VCCI Technical requirements IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.7 Electric field test (1 GHz and over)	ANSI C63.4 with FCC method 47 CFR Part 15 subpart B CISPR 11 (except 10, 12) EN 55011 (except 10, 12) AS/NZS CISPR 11 (except 10, 12) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR 22 (except 7) CISPR 32(only Table A.3,A.5)



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	EN 55032(only Table A.3,A.5) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) VCCI Technical requirements
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.9 Disturbance power tests	CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.10 Harmonic current emission tests	IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-3-2 EN 61000-3-2 JIS C 61000-3-2 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.12 Voltage fluctuation and flicker tests	IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-3-3 EN 61000-3-3 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8)
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.14 Electrostatic discharge immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	IEC 61000-4-2 EN 61000-4-2 JIS C 61000-4-2 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.15 RF radiated electromagnetic field immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-3 EN 61000-4-3 JIS C 61000-4-3 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.16 Electrical fast transient / burst tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-4 EN 61000-4-4 JIS C 61000-4-4 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.17 Surge immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	JIS C 8281-2-1 26 IEC 61000-4-5 EN 61000-4-5 JIS C 61000-4-5 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.18 RF conducted immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-6 EN 61000-4-6 JIS C 61000-4-6 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.19 Power frequency magnetic field immunity tests	IEC 60601-1-2 EN 60601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-8 EN 61000-4-8, JIS C 61000-4-8 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 IEC 61326-1 EN 61326-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.20 Voltage dips, short interruptions and voltage variations immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-11 EN 61000-4-11 JIS C 61000-4-11 IEC 61000-6-1 EN 61000-6-1



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 except test of three phase equipment
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.21 Immunity tests for Information technology equipment	CISPR 24 EN 55024
M21.34 Household and Similar Equipment Electromagnetic fields of household appliances and similar apparatus with regard to human exposure	IEC 62233 EN 62233



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Address	1048, Kadoma, Kadoma-shi, Osaka, 571-8686 Japan

1) Premises on which testing activities are performed

Name of Premise	Panasonic Corporation Analysis Center EMC Test Laboratory Sasayama EMC Site	
Address of Premise	Zip	669-2356
	Address	231-1, Yashiro, Sasayama City, Hyogo ,Japan
Testing service at permanent facilities or on site testing service	<input checked="" type="checkbox"/> Testing service at permanent facilities <input type="checkbox"/> On site testing service	

Scope of Accreditation

CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.1 Continuous disturbance tests	ANSI C63.4 with FCC method 47 CFR Part 15 subpart B FCC method 47 CFR Part 18 (using MP-5) CISPR 11 (except 10, 12) EN 55011 (except 10, 12) AS/NZS CISPR 11 (except 10, 12) CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) CISPR 15 (except 10) EN 55015 (except 10) AS/NZS CISPR 15 (except 10) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR 22 (except 7) CISPR 32(only Table A.8,A.9) EN 55032(only Table A.8,A.9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11)



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Type of Laboratory	Testing Laboratory
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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	JIS B 3502 8 to 10 (except 9.11) IEC 61326-1 EN 61326-1 VCCI Technical requirements IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.3 Discontinuous disturbance tests	CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11)
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.4 Conducted emission tests at telecommunication ports	CISPR 15 (except 10) EN 55015 (except 10) AS/NZS CISPR 15 (except 10) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR 22 (except 7) CISPR 32(only Table A.10,A.11) EN 55032(only Table A.10,A.11) IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) VCCI Technical requirements IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing	CISPR 11 (except 10, 12) EN 55011 (except 10, 12) AS/NZS CISPR 11 (except 10, 12)



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
M21.4.5 Magnetic field test (Less than 30 MHz)	CISPR 15 (except 10) EN 55015 (except 10) AS/NZS CISPR 15 (except 10) IEC 60669-2-1 26 EN 60669-2-1 26
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.6 Electric field test (30 MHz to 1 GHz)	ANSI C63.4 with FCC method 47 CFR Part 15 subpart B FCC method 47 CFR Part 18 (using MP-5) CISPR 11 (except 10, 12) EN 55011 (except 10, 12) AS/NZS CISPR 11 (except 10, 12) CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) CISPR 15 (30 MHz to 300 MHz) EN 55015 (30 MHz to 300 MHz) AS/NZS CISPR 15 (30 MHz to 300 MHz) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR 22 (except 7) CISPR 32(only Table A.2,A.4) EN 55032(only Table A.2,A.4) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61326-1 EN 61326-1 VCCI Technical requirements IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.7 Electric field test (1	ANSI C63.4 with FCC method 47 CFR Part 15 subpart B FCC method 47 CFR Part 18 (using MP-5) CISPR 11 (except 10, 12) EN 55011 (except 10, 12)



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
GHz and over)	AS/NZS CISPR 11 (except 10, 12) CISPR 22 (except 7) EN 55022 (except 7) AS/NZS CISPR 22 (except 7) CISPR 32(only Table A.3,A.5) EN 55032(only Table A.3,A.5) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC 61000-6-4 (except 8) EN 61000-6-4 (except 8) VCCI Technical requirements only below 18 GHz
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.9 Disturbance power tests	CISPR 14-1 (except 8) EN 55014-1 (except 8) AS/NZS CISPR 14-1 (except 8) IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.10 Harmonic current emission tests	IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-3-2 EN 61000-3-2 JIS C 61000-3-2 IEC 61000-3-12 EN 61000-3-12 IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8) IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.12 Voltage fluctuation and flicker tests	IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-3-3 EN 61000-3-3 IEC 61000-3-11 EN 61000-3-11



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	IEC 61000-6-3 (except 8) EN 61000-6-3 (except 8)
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.14 Electrostatic discharge immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-2 EN 61000-4-2 JIS C 61000-4-2 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547, EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC61326-3-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.15 RF radiated electromagnetic field immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-3 EN 61000-4-3 JIS C 61000-4-3



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC61326-3-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.16 Electrical fast transient / burst tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-4 EN 61000-4-4 JIS C 61000-4-4 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1



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CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	IEC61326-3-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.17 Surge immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 JIS T 0601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-5 EN 61000-4-5 JIS C 61000-4-5 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC61326-3-1 IEC62040-2 JIS C 4411-2 except test of 10/700us
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.18 RF conducted immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-6



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Type of Laboratory	Testing Laboratory
Name of Laboratory	Panasonic Corporation Analysis Center EMC Test Laboratory
Address	1048, Kadoma, Kadoma-shi, Osaka, 571-8686 Japan

CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	EN 61000-4-6 JIS C 61000-4-6 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC61326-3-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.19 Power frequency magnetic field immunity tests	IEC 60601-1-2 EN 60601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-8 EN 61000-4-8 JIS C 61000-4-8 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 IEC 61326-1 EN 61326-1



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Accreditation Certificate

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Type of Laboratory	Testing Laboratory
Name of Laboratory	Panasonic Corporation Analysis Center EMC Test Laboratory
Address	1048, Kadoma, Kadoma-shi, Osaka, 571-8686 Japan

CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
	IEC61326-3-1 IEC62040-2 JIS C 4411-2
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.20 Voltage dips, short interruptions and voltage variations immunity tests	CISPR 14-2 (except 9) EN 55014-2 (except 9) IEC 60601-1-2 EN 60601-1-2 IEC 60669-2-1 26 EN 60669-2-1 26 JIS C 8281-2-1 26 IEC 61000-4-11 EN 61000-4-11 JIS C 61000-4-11 IEC 61000-6-1 EN 61000-6-1 JIS C 61000-6-1 IEC 61000-6-2 EN 61000-6-2 JIS C 61000-6-2 IEC 61131-2 8 to 10 (except 9.11) EN 61131-2 8 to 10 (except 9.11) JIS B 3502 8 to 10 (except 9.11) IEC 61547 EN 61547 EN 50130-4 IEC 61326-1 EN 61326-1 IEC61326-3-1 except test of three phase equipment
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.21 Immunity tests for Information technology equipment	CISPR 24 EN 55024
M21 Electrical testing M21.4 Electromagnetic compatibility testing M21.4.2.11 Immunity to	IEC 61000-4-16 EN 61000-4-16 JIS C 61000-4-16 IEC61326-3-1

Accreditation No.

RTL02730

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Type of Laboratory	Testing Laboratory
Name of Laboratory	Panasonic Corporation Analysis Center EMC Test Laboratory
Address	1048, Kadoma, Kadoma-shi, Osaka, 571-8686 Japan

CODE OF CLASSIFICATION NAME	TEST METHOD STANDARD
conducted, common mode disturbance in the frequency range 0 Hz - 150 kHz	except test of three phase equipment and communication line
M21.34 Household and Similar Equipment Electromagnetic fields of household appliances and similar apparatus with regard to human exposure	IEC 62233 EN 62233

Japan Accreditation Board